

Notice of References Cited	Application/Control No. 10/665,435	Applicant(s)/Patent Under Reexamination YU ET AL.	
	Examiner Thuy V. Tran	Art Unit 2821	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,693,609	02-2004	Lee et al.	345/63
*	D	US-6,473,061	10-2002	Lim et al.	345/60
*	E	US-5,943,032	08-1999	Nagaoka et al.	345/63
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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